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Foreword

Almost everyone dealing with surface analysis of insulating materials has encountered blurring/shifts of the images and/or the peaks due to sample charging, and has also learned how to cope with this “nuisance”, thanks to excellent technical developments all along. Only very few researchers have thought of benefiting from this shortcoming and turned it into “a blessing”, like most of the authors in this issue. Therefore, the present special issue has been put together to review and highlight the recent work of some prominent scientists around the world dealing with the “charging”. We hope that this issue will add to a better understanding at the molecular level, of this very fundamental phenomenon, which is well known to humankind for more than 25 centuries.

I am grateful to Jean-Jacques Pireaux for suggesting the idea, to Michael Kelly for writing the “Historical Perspective”, to Peter

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